

2N1870A-2N1874A

SILICON CONTROLLED RECTFIERS

FEATURES

- Available as "HR" (high reliability) screened per MIL-PRF-19500, JANTX level. Add "HR" suffix to base part number.
- Available as non-RoHS (Sn/Pb plating), standard, and as RoHS by adding "-PBF" suffix.

MAXIMUM RATINGS

Ratings	Symbol	2N1870A	2N1871A	2N1872A	2N1873A	2N1874A	Unit
Repetitive peak off state voltage	V _{DRM}	30	60	100	150	200	V
Repetitive peak reverse voltage	V _{RRM}	30	60	100	150	200	V
DC on state current							
100°C ambient	Ι _Τ			250			mA
100°C case				1.25			Α
Repetitive peak on state current	I _{TRM}			Up to 30			Α
Peak one cycle surge (non-repetitive) on state current	I _{TSM}			15			А
Peak gate current	I _{GM}			250			mA
Average gate current	I _{G(AV)}			25			mA
Reverse gate voltage	V_{GR}			5			V
Thermal resistance, junction to case	R _{eJC}			20			°C/W
Operating and storage temperature range	T _J , T _{stg}			-65 to 150			°C

ELECTRICAL CHARACTERISTICS (T_A = 25°C unless otherwise specified)

Test	Symbol	Min.	Тур.	Max.	Units	Test Conditions
25°C tests		1		1	l	J
Off-state current	I _{DRM}	-	0.5	10	μΑ	R _{GK} = 1K, V _{DRM} = +rating
Reverse current	I _{RRM}	-	0.5	10	μΑ	R _{GK} = 1K, V _{RRM} = - rating
Gate trigger voltage	V _{GT}	0.4	0.55	0.8	V	R _{GS} = 100ohms, V _D = 5V
Gate trigger current	I _{GT}	-	30	200	μΑ	R _{GS} > 10K ohms, V _D = 5V
On-state voltage	V _{TM}	-	1.8	2.5	V	I _{TM} = 2A (pulse test)
Off-state voltage – critical rate of rise	dv _c /dt	100	-	-	V/µs	Specified test circuit
Reverse gate current	I _{GR}	-	0.5	10	μΑ	V _{GRM} = 5V, anode open
Holding current	lн	0.3	-	5.0	mA	$I_G = -150 \mu A$, $V_D = 5 V$
125°C tests						
High temperature off state current	I _{DRM}	-	15	100	μΑ	R _{GK} = 1K, V _{DRM} = + rating
High temperature reverse current	I _{RRM}	-	15	100	μΑ	R _{GK} = 1K, V _{RRM} = - rating
High temperature gate non-trigger voltage	V_{GD}	0.2	-	-	V	R_{GS} = 100 ohms, V_D = 5V
High temperature holding current	lн	0.2	-	-	mA	$I_G = -150 \mu A$, $V_D = 5 V$
-65 °C tests						
Low temperature gate trigger voltage	V _{GT}	-	-	1.0	V	R _{GK} = 100 ohms, V _D = 5V
Low temperature gate trigger current	I _{GT}	-	-	500	μΑ	R _{GK} > 10K ohms, V _D = 5V
Low temperature holding current	I _H	-	-	15	mA	$I_G = -150 \mu A, V_D = 5V$

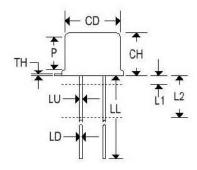
Voltage ratings apply over the full operating temperature range provided the gate is connected to the cathode through a resistor, 1K or smaller, or other adequate gate bias is used.



MECHANICAL CHARACTERISTICS

Case:	TO-5
Marking:	Alpha numberic
Pin out:	See below

TV E B2 LO HD



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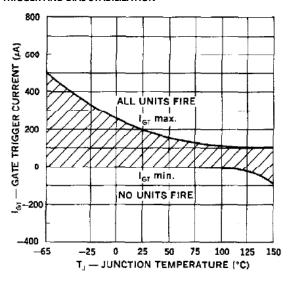
Dim	TO-5							
	Inc	hes	Millimeters					
	Min	Max	Min	Max				
HD	0.335	0.370	8.510	9.400				
CD	0.305	0.335	7.750	8.510				
CH	0.240	0.260	6.100	6.600				
LL	1.500	(5)	38.100	15				
LD	0.016	0.021	0.410	0.530				
LU	0.016	0.019	0.410	0.480				
Р	0.100	-	2.540	- 2				
TL	0.029	0.045	0.740	1.140				
TW	0.028	0.034	0.710	0.860				
TH	0.009	0.125	0.230	3.180				
LO	0.141 NOM		3.590 NOM					
а	45°TP		45°TP					



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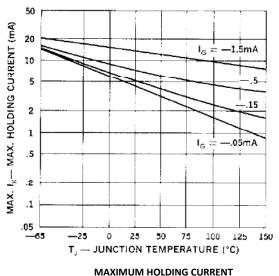
SILICON CONTROLLED RECTFIERS

TRIGGER AND BIAS STABILIZATION

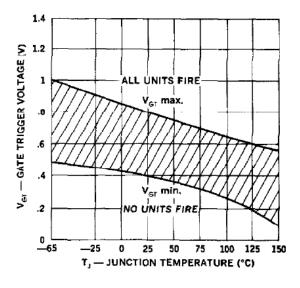


GATE TRIGGER CURRENT

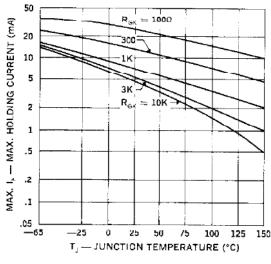
HOLDING CURRENT



(CURRENT BIAS)



GATE TRIGGER VOLTAGE



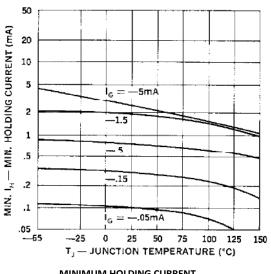
MAXIMUM HOLDING CURRENT (RESISTOR BIAS)



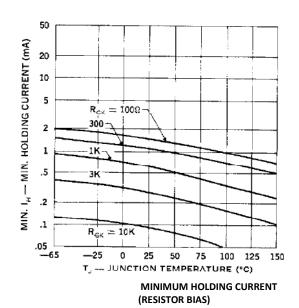
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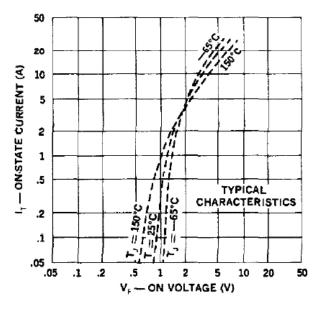
HOLDING CURRENT



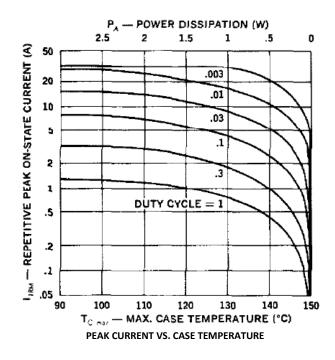
MINIMUM HOLDING CURRENT (CURRENT BIAS)



CURRENT RATINGS - THERMAL DESIGN



ON-STATE CURRENT VS VOLTAGE

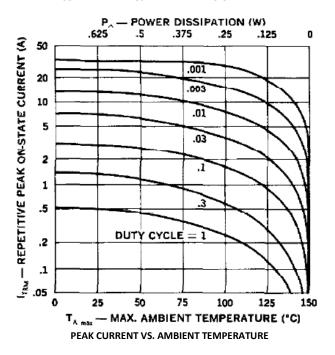




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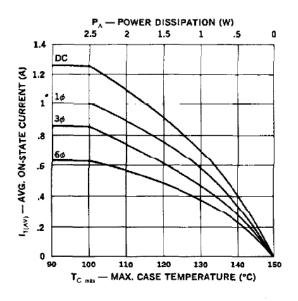
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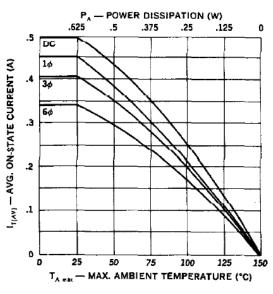
CURRENT RATINGS - THERMAL DESIGN



50 (BEFORE SURGE = 0 20 - PEAK SURGE CURRENT (A) 10 5 SOLID LINE: RATED $T_{\rm C} = 100^{\circ}{\rm C}$ BLOCKING VOLTAGE MAY BE APPLIED IMMEDIATELY AFTER SURGE .5 DASH LINE: BLOCKING VOLTAGE MAY NOT BE SUSTAINED FOR 0.1 SECONDS .2 AFTER SURGE .1 .05 10-5 10-4 10-3 10-2 10-1 1 102 103 SURGE DURATION (s)

SURGE CURRENT VS. TIME





AVERAGE CURRENT VS. AMBIENT TEMPERATURE